DATASHEET

HI5728

RENESAS

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10-Bit, 125/60MSPS, Dual High Speed CMOS D/A Converter

FN4321 Rev 5.00 January 22, 2010

The HI5728 is a 10-bit, dual 125MSPS D/A converter which is implemented in an advanced CMOS process. It is designed for high speed applications where integration, bandwidth and accuracy are essential. Operating from a single +5V or +3V supply, the converter provides 20.48mA of full scale output current and includes an input data register. Low glitch energy and excellent frequency domain performance are achieved using a segmented architecture. A 60MSPS version and an 8-bit (HI5628) version are also available. Comparable single DAC solutions are the HI5760 (10-bit) and the HI5660 (8-bit).

Ordering Information

PART NUMBER	PART MARKING	TEMP. RANGE (°C)	PACKAGE	PKG. DWG. #	MAX CLOCK SPEED (MHz)
HI5728IN*	HI5728IN	-40 to +85	48 Ld LQFP	Q48.7x7A	125
HI5728INZ* (Note)	HI5728INZ	-40 to +85	48 Ld LQFP (Pb-free)	Q48.7x7A	125
HI5728/6IN	HI5728/6IN	-40 to +85	48 Ld LQFP	Q48.7x7A	60
HI5728/6INZ (Note)	HI5728 /6INZ	-40 to +85	48 Ld LQFP (Pb-free)	Q48.7x7A	60
HI5728EVAL1		+25	Evaluation P	latform	125

*Add "-T" suffix for tape and reel. Please refer to TB347 for details on reel specifications.

NOTE: These Intersil Pb-free plastic packaged products employ special Pb-free material sets, molding compounds/die attach materials, and 100% matte tin plate plus anneal (e3 termination finish, which is RoHS compliant and compatible with both SnPb and Pb-free soldering operations). Intersil Pb-free products are MSL classified at Pb-free peak reflow temperatures that meet or exceed the Pb-free requirements of IPC/JEDEC J STD-020.

Features

•	Throughput Rate				•	•			•	•	•	•			•	•	1	2	51	N	SF	29	;

- Integral Linearity Error ±1 LSB
 Differential Linearity ±0.5 LSB
- Gain Matching (Typ).....0.5%
- Single Power Supply from +5V to +3V
- CMOS Compatible Inputs
- Excellent Spurious Free Dynamic Range
- Internal Voltage Reference
- Dual 10-Bit D/A Converters on a Monolithic Chip
- · Pb-Free Available (RoHS Compliant)

Applications

- Wireless Local Loop
- · Direct Digital Frequency Synthesis
- Wireless Communications
- Signal Reconstruction
- Arbitrary Waveform Generators
- Test Equipment/Instrumentation
- High Resolution Imaging Systems



Pinout





Functional Block Diagram





Typical Applications Circuit



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Pin Descriptions

PIN NO.	PIN NAME	PIN DESCRIPTION
39, 38, 37, 36, 35, 34, 33, 32, 31, 30	QD9 (MSB) Through QD0 (LSB)	Digital Data Bit 9, the Most Significant Bit through Digital Data Bit 0, the Least Significant Bit, of the Q channel.
1, 2, 3, 4, 5, 6, 7, 46, 47, 48	ID9 (MSB) Through ID0 (LSB)	Digital Data Bit 9, the Most Significant Bit through Digital Data Bit 0, the Least Significant Bit, of the I channel.
8	SLEEP	Control Pin for Power-Down mode. Sleep Mode is active high; Connect to ground for Normal Mode. Sleep pin has internal 20µA active pull-down current.
15	REFLO	Connect to analog ground to enable internal 1.2V reference or connect to AV _{DD} to disable.
23	REFIO	Reference voltage input if internal reference is disabled and reference voltage output if internal reference is enabled. Use 0.1μ F cap to ground when internal reference is enabled.
22	FSADJ	Full Scale Current Adjust. Use a resistor to ground to adjust full scale output current. Full Scale Output Current Per Channel = $32 \times I_{FSADJ}$.
14, 24	ICOMP1, QCOMP1	Reduces noise. Connect each to AV_{DD} with 0.1μ F capacitor near each pin. The ICOMP1 and QCOMP1 pins MUST be tied together externally.
13, 18, 19, 25	AGND	Analog Ground Connections.
17	IOUTB	The complimentary current output of the I channel. Bits set to all 0s gives full scale current.
16	IOUTA	Current output of the I channel. Bits set to all 1s gives full scale current.
20	QOUTB	The complimentary current output of the Q channel. Bits set to all 0s gives full scale current.
21	QOUTA	Current output of the Q channel. Bits set to all 1s gives full scale current.
11, 27	NC	No Connect. Recommended: connect to ground.
12, 26	AV _{DD}	Analog Supply (+2.7V to +5.5V).
10, 28, 41, 44	DGND	Digital Ground.
9, 29, 40, 45	DV _{DD}	Supply voltage for digital circuitry (+2.7V to +5.5V).
43	ICLK	Clock input for I channel. Positive edge of clock latches data.
42	QCLK	Clock input for Q channel. Positive edge of clock latches data.

Absolute Maximum Ratings

Internal Reference Output Current. ±50µA Reference Input Voltage Range. AV _{DD} +0.3V Analog Output Current (I _{OUT}) 24mA

Operating Conditions

Thermal Information

Thermal Resistance (Typical, Note 1)	θ _{JA} (°C/W)
48 Ld TQFP Package	55
Maximum Power Dissipation	
48 Ld TQFP Package	930mW
Maximum Junction Temperature	+150°C
Maximum Storage Temperature Range65°	C to +150°C
Pb-Free Reflow Profile	e link below
http://www.intersil.com/pbfree/Pb-FreeReflow.asp	

CAUTION: Do not operate at or near the maximum ratings listed for extended periods of time. Exposure to such conditions may adversely impact product reliability and result in failures not covered by warranty.

NOTE:

1. θ_{JA} is measured with the component mounted on a high effective thermal conductivity test board in free air. See Tech Brief TB379 for details.

Electrical Specifications	AV _{DD} = DV _{DD} = +5V, V _{REF} = Internal 1.2V, IOUTFS = 20mA, T _A = +25°C for All Typical Values. Data given is
	per channel except for "POWER SUPPLY CHARACTERISTICS" on page 8

SYSTEM PERFORMANCE (Per Channel) Resolution 10 - - Ferrican Integral Linearity Error, INL "Best Fit" Straight Line (Note 7) -1 ±0.5 ±1.1 L Differential Linearity Error, INL "Best Fit" Straight Line (Note 7) -0.5 ±0.25 ±0.5 L Offset Error, IoS (Note 7) -0.025 ±0.25 ±0.025 % Offset Error, IoS (Note 7) -0.025 ±0.025 % % Offset Error, IoS (Note 7) -0.025 ±0.025 % % Offset Error, IoS (Note 7) -0.01 ±2 ±1.0 % Offset Error, FSE With External Reference (Notes 2, 7) -10 ±1 ±1.0 % Full Scale Gain Drift With External Reference (Note 7) - ±50 - ppm Gain Matching Between Channels FOUT = 10MHz - 50 1.0 0.5 - I/Q Channel Isolation FOUT = 10MHz - 80 - - -			-	1157281 0°C TC	N) +85°C		
Resolution 10 - - Itegral Linearity Error, INL "Best Fit" Straight Line (Note 7) -1 ±0.5 +11 L Differential Linearity Error, INL "Best Fit" Straight Line (Note 7) -0.5 ±0.25 +0.55 L Offset Error, IOS (Note 7) -0.025 ±0.25 +0.025 % Offset Drift Coefficient (Note 7) 0.1 ppm Full Scale Gain Error, FSE With External Reference (Notes 2, 7) -10 ±1 +10 % Full Scale Gain Drift With External Reference (Notes 2, 7) -10 ±1 +10 % Full Scale Gain Drift With External Reference (Note 7) - ±50 - ppm Gain Matching Between Channels Vote 3) - ±00 - ppm I/Q Channel Isolation FOUT = 10MHz - 80 - - - Output Voltage Compliance Range (Note 3) - 125 - 20 - Full Scale Output Current, I _{FS} 0.1% (±1 LSB,	PARAMETER	TEST CONDITIONS		ТҮР		UNITS	
Integral Linearity Error, INL "Best Fit" Straight Line (Note 7) -1 ± 0.5 ± 1.0 ± 0.5 Differential Linearity Error, INL (Note 7) -0.5 ± 0.25 ± 0.25 ± 0.25 ± 0.5 ± 1.025 ± 0.55 ± 1.025 ± 0.55 ± 0.255	SYSTEM PERFORMANCE (Per Cha	nnel)		!	ļ	l	
Differential Linearity Error, DNL (Note 7) -0.5 ± 0.25 ± 0.25 ± 0.25 ± 0.025 $\oplus 0.025$	Resolution		10	-	-	Bits	
Offset Error, I _{OS} (Note 7) -0.025 +0.025 % Offset Drift Coefficient (Note 7) - 0.1 - ppm Full Scale Gain Error, FSE With External Reference (Notes 2, 7) -10 ± 2 +10 % Full Scale Gain Drift With External Reference (Notes 2, 7) -10 ± 1 +10 % Full Scale Gain Drift With External Reference (Note 7) - ± 50 - ppm Gain Matching Between Channels With Internal Reference (Note 7) - ± 10 0.5 0.1 0.5 0.1 ppm Gain Matching Between Channels FOUT = 10MHz - 0.05 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.5 0.5 0.1 0.5 0.5 0.5 0.5 0.5 0.5 0.5 0.5 <	Integral Linearity Error, INL	"Best Fit" Straight Line (Note 7)	-1	±0.5	+1	LSB	
Offset Drift Coefficient (Note 7) - 0.1 - pm Full Scale Gain Error, FSE With External Reference (Notes 2, 7) -10 ±2 +10 % Full Scale Gain Drift With Internal Reference (Notes 2, 7) -10 ±1 +10 % Full Scale Gain Drift With External Reference (Note 7) - ±50 - pm Gain Matching Between Channels With Internal Reference (Note 7) - ±100 0.5 pm I/Q Channel Isolation FOUT = 10MHz - 50.1 0.5 1.25 1.25 Vull Channel Isolation FOUT = 10MHz - - 20 - 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25 1.25	Differential Linearity Error, DNL	(Note 7)	-0.5	±0.25	+0.5	LSB	
Full Scale Gain Error, FSEWith External Reference (Notes 2, 7)-10 ± 2 +10%Full Scale Gain DriftWith Internal Reference (Notes 2, 7)-10 ± 1 +10%Full Scale Gain DriftWith External Reference (Note 7)- ± 50 -ppmWith Internal Reference (Note 7)- ± 100 -ppmGain Matching Between Channels ± 100 -ppmI/Q Channel IsolationF _{OUT} = 10MHz-80Output Voltage Compliance Range(Note 3)-1.25Full Scale Output Current, I _{FS} -20-20rDYNAMIC CHARACTERISTICS (Per Channel)0.1% (± 1 LSB, equivalent to 9 Bits) (Note 7)-35-NOutput Settling Time, (t_{SETT})0.1% (± 1 LSB, equivalent to 10 Bits) (Note 7)-35-POutput Rise TimeFull Scale Step-1.5-POutput Rise TimeFull Scale Step-1.5-POutput CapacitanceFull Scale Step-1.5-P	Offset Error, I _{OS}	(Note 7)	-0.025		+0.025	% FSR	
Mith Internal Reference (Notes 2, 7)1.01.11.01.0Full Scale Gain DriftWith External Reference (Note 7)- ± 50 -ppmWith Internal Reference (Note 7)- ± 100 -ppmGain Matching Between Channels- ± 100 -ppmGain Matching Between Channels ± 100 -ppmI/Q Channel IsolationF _{OUT} = 10MHz-80Output Voltage Compliance Range(Note 3)-2-20rFull Scale Output Current, I _{FS} -20-125-NDYNAMIC CHARACTERISTICS (Per Channel)0.1% (± 1 LSB, equivalent to 9 Bits) (Note 7)-20-NOutput Settling Time, (t_{SETT})0.1% (± 1 LSB, equivalent to 10 Bits) (Note 7)-35-POutput Rise TimeFull Scale Step-1.5-POutput Fall TimeFull Scale Step-1.5-POutput CapacitanceFull Scale Step-1.5-P	Offset Drift Coefficient	(Note 7)	-	0.1	-	ppm FSR/°C	
Full Scale Gain DriftWith External Reference (Note 7) $ \pm$ 50 ppm Gain Matching Between Channels··· \pm 100··· ppm Gain Matching Between ChannelsFOUT = 10MHz··· 0.5 0.1 0.5 0.1 I/Q Channel Isolation $F_{OUT} = 10MHz$ ··· 80 ··· 1.25 0.1 Output Voltage Compliance Range(Note 3)··· 1.25 0.1 20 1.25 Full Scale Output Current, IFS··· 2 ··· 20 0.1 DYNAMIC CHARACTERISTICS (Per Channel)··· 125 ··· 0.1% 0.1% Maximum Clock Rate, f_{CLK} (Note 3) 125 ··· 0.5% 0.1% Output Settling Time, (t _{SETT}) 0.1% (\pm 1 LSB, equivalent to 9 Bits) (Note 7)··· 35 ··· 0.5% Singlet Glitch Area (Peak Glitch) $R_L = 25\Omega$ (Note 7)··· 35 ··· 0.5% Output Rise TimeFull Scale Step··· 1.5 ··· 0.5% ···Output Fall TimeFull Scale Step··· 1.5 ··· 0.5% Output Capacitance··· 0.5% ··· 0.5% ··· 0.5%	Full Scale Gain Error, FSE	With External Reference (Notes 2, 7)	-10	±2	+10	% FSR	
With Internal Reference (Note 7) - ±100 - ppm Gain Matching Between Channels -0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 0.1 0.5 1.25 0.5 0.5 0.5 1.25 0.5 1.25 0.5 0.5 1.25 0.5 1.5 0.5 0.5 1.5 0.5 1.5 0.5 0.5 1.5 1.5 0.5 1.5 0.5 1.5 0.5 1.5 0.5 1.5 0.5 1.5 0.5 1.5 0.5 1.5 1.5 1.5		With Internal Reference (Notes 2, 7)	-10	±1	+10	% FSR	
Gain Matching Between Channels-0.50.10.51I/Q Channel Isolation $F_{OUT} = 10$ MHz-80-60Output Voltage Compliance Range(Note 3)-0.3-1.2560Full Scale Output Current, I _{FS} 2-2070DYNAMIC CHARACTERISTICS (Per Channel)Maximum Clock Rate, f_{CLK} (Note 3)125NOutput Settling Time, (t _{SETT})0.1% (±1 LSB, equivalent to 9 Bits) (Note 7)-20-10.05% (±1/2 LSB, equivalent to 10 Bits) (Note 7)-35Singlet Glitch Area (Peak Glitch) $R_L = 25\Omega$ (Note 7)-35-pOutput Rise TimeFull Scale Step-1.5-1Output CapacitanceFull Scale Step-1.5-1	Full Scale Gain Drift	With External Reference (Note 7)	-	±50	-	ppm FSR/°C	
I/Q Channel Isolation $F_{OUT} = 10MHz$ -80-80-Output Voltage Compliance Range(Note 3)-0.3-0.3-1.25-Full Scale Output Current, I _{FS} 2-20rDYNAMIC CHARACTERISTICS (Per Channel)Maximum Clock Rate, f _{CLK} (Note 3)125NOutput Settling Time, (t _{SETT})0.1% (±1 LSB, equivalent to 9 Bits) (Note 7)-200.05% (±1/2 LSB, equivalent to 10 Bits) (Note 7)-35Singlet Glitch Area (Peak Glitch) $R_L = 25\Omega$ (Note 7)-35-pOutput Rise TimeFull Scale Step-1.5Output Capacitance-1.5		With Internal Reference (Note 7)	-	±100	-	ppm FSR/°C	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gain Matching Between Channels		-0.5	0.1	0.5	dB	
Full Scale Output Current, IFSConstrained2-20DYNAMIC CHARACTERISTICS (Per Channel)Maximum Clock Rate, f_{CLK} (Note 3)125NOutput Settling Time, (tSETT) 0.1% (±1 LSB, equivalent to 9 Bits) (Note 7)-20-N 0.05% (±1/2 LSB, equivalent to 10 Bits) (Note 7)-35NSinglet Glitch Area (Peak Glitch) $R_L = 25\Omega$ (Note 7)-35-POutput Rise TimeFull Scale Step-1.5Output Fall TimeFull Scale Step-1.5Output Capacitance-10-10-	I/Q Channel Isolation	F _{OUT} = 10MHz	-	80	-	dB	
DYNAMIC CHARACTERISTICS (Per Channel)Maximum Clock Rate, f_{CLK} (Note 3)125NOutput Settling Time, (t_{SETT}) 0.1% (±1 LSB, equivalent to 9 Bits) (Note 7)-20 0.05% (±1/2 LSB, equivalent to 10 Bits) (Note 7)-35Singlet Glitch Area (Peak Glitch) R_L = 25 Ω (Note 7)-35Output Rise TimeFull Scale Step-1.5Output Fall TimeFull Scale Step-1.5Output Capacitance-1.0-10	Output Voltage Compliance Range	(Note 3)	-0.3	-	1.25	V	
Maximum Clock Rate, f_{CLK} (Note 3)125NOutput Settling Time, (t_{SETT}) 0.1% (±1 LSB, equivalent to 9 Bits) (Note 7)-20 0.05% (±1/2 LSB, equivalent to 10 Bits) (Note 7)-35PSinglet Glitch Area (Peak Glitch) $R_L = 25\Omega$ (Note 7)-35-POutput Rise TimeFull Scale Step-1.5Output Fall TimeFull Scale Step-1.5Output Capacitance-1.0-10	Full Scale Output Current, I _{FS}		2	-	20	mA	
Output Settling Time, (tSETT) 0.1% (±1 LSB, equivalent to 9 Bits) (Note 7) $ 20$ $ 0.05\%$ (±1/2 LSB, equivalent to 10 Bits) (Note 7) $ 35$ $-$ Singlet Glitch Area (Peak Glitch) $R_L = 25\Omega$ (Note 7) $ 35$ $ p$ Output Rise TimeFull Scale Step $ 1.5$ $ 1.5$ $-$ Output Fall TimeFull Scale Step $ 1.5$ $ 1.5$ $-$ Output Capacitance $ 1.0$ $ 1.0$ $-$	DYNAMIC CHARACTERISTICS (Per	Channel)	I			I	
$\begin{tabular}{ c c c c c c c c c c c c c c c c c c c$	Maximum Clock Rate, f _{CLK}	(Note 3)	125	-	-	MHz	
Singlet Glitch Area (Peak Glitch) $R_L = 25\Omega$ (Note 7)-35-pOutput Rise TimeFull Scale Step-1.5Output Fall TimeFull Scale Step-1.5Output Capacitance-1.0-10-	Output Settling Time, (t _{SETT})	0.1% (±1 LSB, equivalent to 9 Bits) (Note 7)	-	20	-	ns	
Output Rise TimeFull Scale Step-1.5-Output Fall TimeFull Scale Step-1.5-Output Capacitance-10-		0.05% (±1/2 LSB, equivalent to 10 Bits) (Note 7)	-	35	-	ns	
Output Fall TimeFull Scale Step-1.5-Output Capacitance-10-	Singlet Glitch Area (Peak Glitch)	R _L = 25Ω (Note 7)	-	35	-	pV•s	
Output Capacitance - 10 -	Output Rise Time	Full Scale Step	-	1.5	-	ns	
	Output Fall Time	Full Scale Step	-	1.5	-	ns	
	Output Capacitance		-	10	-	pF	
Output Noise IOUTFS = 20mA - 50 - pA	Output Noise	IOUTFS = 20mA	-	50	-	pA/√Hz	
IOUTFS = 2mA - 30 - pA		IOUTFS = 2mA	-	30	-	pA/√Hz	

Electrical Specifications $AV_{DD} = DV_{DD} = +5V$, $V_{REF} = Internal 1.2V$, IOUTFS = 20mA, $T_A = +25^{\circ}C$ for All Typical Values. Data given is per channel except for "POWER SUPPLY CHARACTERISTICS" on page 8 (Continued)

			II5728I 0°C TC	N) +85°C	
		MIN		MAX	
		(Note 11)	TYP	(Note 11)	UNITS
AC CHARACTERISTICS (Per Chan	,				
Spurious Free Dynamic Range, SFDR Within a Window	f _{CLK} = 125MSPS, f _{OUT} = 32.9MHz, 10MHz Span (Notes 4, 7)	-	75	-	dBc
	f _{CLK} = 100MSPS, f _{OUT} = 5.04MHz, 4MHz Span (Notes 4, 7)	-	76	-	dBc
	f_{CLK} = 60MSPS, f_{OUT} = 10.1MHz, 10MHz Span (Notes 4, 7)	-	75	-	dBc
	f_{CLK} = 50MSPS, f_{OUT} = 5.02MHz, 2MHz Span (Notes 4, 7)	-	76	-	dBc
	f_{CLK} = 50MSPS, f_{OUT} = 1.00MHz, 2MHz Span (Notes 4, 7)	-	78	-	dBc
Total Harmonic Distortion (THD) to Nyquist	f _{CLK} = 100MSPS, f _{OUT} = 2.00MHz (Notes 4, 7)	-	71	-	dBc
, yqulot	f _{CLK} = 50MSPS, f _{OUT} = 2.00MHz (Notes 4, 7)	-	71	-	dBc
	f _{CLK} = 50MSPS, f _{OUT} = 1.00MHz (Notes 4, 7)	-	76	-	dBc
Spurious Free Dynamic Range, SFDR to Nyquist	f _{CLK} = 125MSPS, f _{OUT} = 32.9MHz, 62.5MHz Span (Notes 4, 7)	-	54	-	dBc
	f _{CLK} = 125MSPS, f _{OUT} = 10.1MHz, 62.5MHz Span (Notes 4, 7)	-	64	-	dBc
	f _{CLK} = 100MSPS, f _{OUT} = 40.4MHz, 50MHz Span (Notes 4, 7)	-	52	-	dBc
	f _{CLK} = 100MSPS, f _{OUT} = 20.2MHz, 50MHz Span (Notes 4, 7)	-	60	-	dBc
	f _{CLK} = 100MSPS, f _{OUT} = 5.04MHz, 50MHz Span (Notes 4, 7)	-	68	-	dBc
	f _{CLK} = 100MSPS, f _{OUT} = 2.51MHz, 50MHz Span (Notes 4, 7)	-	74	-	dBc
	f _{CLK} = 60MSPS, f _{OUT} = 10.1MHz, 30MHz Span (Notes 4, 7)	-	63	-	dBc
	f _{CLK} = 50MSPS, f _{OUT} = 20.2MHz, 25MHz Span (Notes 4, 7)	-	55	-	dBc
	f _{CLK} = 50MSPS, f _{OUT} = 5.02MHz, 25MHz Span (Notes 4, 7)	-	68	-	dBc
	f _{CLK} = 50MSPS, f _{OUT} = 2.51MHz, 25MHz Span (Notes 4, 7)	-	73	-	dBc
	f _{CLK} = 50MSPS, f _{OUT} = 1.00MHz, 25MHz Span (Notes 4, 7)	-	73	-	dBc
AC CHARACTERISTICS (Per Chan	nel) - HI5728/6IN - 60MHz				
Spurious Free Dynamic Range,	f _{CLK} = 60MSPS, f _{OUT} = 10.1MHz, 10MHz Span (Notes 4, 7)	-	75	-	dBc
SFDR Within a Window	f _{CLK} = 50MSPS, f _{OUT} = 5.02MHz, 2MHz Span (Notes 4, 7)	-	76	-	dBc
	f _{CLK} = 50MSPS, f _{OUT} = 1.00MHz, 2MHz Span (Notes 4, 7)	-	78	-	dBc
Total Harmonic Distortion (THD) to	f _{CLK} = 50MSPS, f _{OUT} = 2.00MHz (Notes 4, 7)	-	71	-	dBc
Nyquist	f _{CLK} = 50MSPS, f _{OUT} = 1.00MHz (Notes 4, 7)	-	76	-	dBc
Spurious Free Dynamic Range,	f _{CLK} = 60MSPS, f _{OUT} = 20.2MHz, 30MHz Span (Notes 4, 7)	-	56	-	dBc
SFDR to Nyquist	f _{CLK} = 60MSPS, f _{OUT} = 10.1MHz, 30MHz Span (Notes 4, 7)	-	63	-	dBc
	f _{CLK} = 50MSPS, f _{OUT} = 20.2MHz, 25MHz Span (Notes 4, 7)	-	55	-	dBc
	f _{CLK} = 50MSPS, f _{OUT} = 5.02MHz, 25MHz Span (Notes 4, 7)	-	68	-	dBc
	f _{CLK} = 50MSPS, f _{OUT} = 2.51MHz, 25MHz Span (Notes 4, 7)	-	73	-	dBc
	f _{CLK} = 50MSPS, f _{OUT} = 1.00MHz, 25MHz Span (Notes 4, 7)	-	73	-	dBc
	f _{CLK} = 25MSPS, f _{OUT} = 5.02MHz, 25MHz Span (Notes 4, 7)	-	71	-	dBc
VOLTAGE REFERENCE		I		I	
Internal Reference Voltage, V _{FSADJ}	Voltage at Pin 22 with Internal Reference	1.04	1.16	1.28	V
Internal Reference Voltage Drift		-	±60	-	ppm/°C
Internal Reference Output Current Sink/Source Capability		-	0.1	-	μA
Reference Input Impedance		-	1	-	MΩ
Reference Input Multiplying Bandwidth	(Note 7)	-	1.4	-	MHz
DIGITAL INPUTS D9-D0, CLK (Per	Channel)	<u> </u>			
Input Logic High Voltage with 5V Supply, V _{IH}	(Note 3)	3.5	5	-	V

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Electrical Specifications $AV_{DD} = DV_{DD} = +5V$, $V_{REF} = Internal 1.2V$, IOUTFS = 20mA, $T_A = +25^{\circ}C$ for All Typical Values. Data given is per channel except for "POWER SUPPLY CHARACTERISTICS" on page 8 (Continued)

		+ T _A = -4				
PARAMETER	TEST CONDITIONS	MIN (Note 11)	ТҮР	MAX (Note 11)	UNITS	
Input Logic High Voltage with 3V Supply, V _{IH}	(Note 3)	2.1	3	-	V	
Input Logic Low Voltage with 5V Supply, V _{IL}	(Note 3)	-	0	1.3	V	
Input Logic Low Voltage with 3V Supply, V _{IL}	(Note 3)	-	0	0.9	V	
Input Logic Current, IIH		-10	-	+10	μA	
Input Logic Current, IIL		-10	-	+10	μA	
Digital Input Capacitance, CIN		-	5	-	pF	
TIMING CHARACTERISTICS (Per C	hannel)			· "		
Data Setup Time, t _{SU}	See Figure 41 (Note 3)	3	-	-	ns	
Data Hold Time, t _{HLD}	See Figure 41 (Note 3)	3	-	-	ns	
Propagation Delay Time, t _{PD}	See Figure 41	-	1	-	ns	
CLK Pulse Width, t _{PW1} , t _{PW2}	See Figure 41 (Note 3)	4	-	-	ns	
POWER SUPPLY CHARACTERIST	cs			1 1		
AVDD Power Supply	(Notes 8, 9)	2.7	5.0	5.5	V	
DVDD Power Supply	(Notes 8, 9)	2.7	5.0	5.5	V	
Analog Supply Current (I _{AVDD})	(5V or 3V, IOUTFS = 20mA)	-	46	60	mA	
	(5V or 3V, IOUTFS = 2mA)	-	8	-	mA	
Digital Supply Current (I _{DVDD})	(5V, IOUTFS = Don't Care) (Note 5)	-	6	10	mA	
	(3V, IOUTFS = Don't Care) (Note 5)	-	3	-	mA	
Supply Current (I _{AVDD}) Sleep Mode	(5V or 3V, IOUTFS = Don't Care)	-	3.2	6	mA	
Power Dissipation	(5V, IOUTFS = 20mA) (Note 6)	-	330	-	mW	
	(5V, IOUTFS = 2mA) (Note 6)	-	140	-	mW	
	(3V, IOUTFS = 20mA) (Note 6)	-	170	-	mW	
	(3V, IOUTFS = 2mA) (Note 6)	-	54	-	mW	
	(5V, IOUTFS = 20mA) (Note 10)	-	300	-	mW	
	(3.3V, IOUTFS = 20mA) (Note 10)	-	150	-	mW	
	(3V, IOUTFS = 20mA) (Note 10)	-	135	-	mW	
Power Supply Rejection	Single Supply (Note 7)	-0.2	-	+0.2	% FSR/V	

NOTES:

- 2. Gain Error measured as the error in the ratio between the full scale output current and the current through R_{SET} (typically 625 μ A). Ideally the ratio should be 32.
- 3. Limits established by characterization and are not production tested.
- 4. Spectral measurements made with differential coupled transformer and 100% amplitude.
- 5. Measured with the clock at 50MSPS and the output frequency at 1MHz, both channels.
- 6. Measured with the clock at 100MSPS and the output frequency at 40MHz, both channels.
- 7. See "Definition of Specifications" on page 16.
- 8. For operation below 3V, it is recommended that the output current be reduced to 12mA or less to maintain optimum performance. DV_{DD} and AV_{DD} do not have to be equal.
- 9. For operation above 125MHz, it is recommended that the power supply be 3.3V or greater. The part is functional with the clock above 125MSPS and the power supply below 3.3V, but performance is degraded.
- 10. Measured with the clock at 60MSPS and the output frequency at 10MHz, both channels.
- 11. Parameters with MIN and/or MAX limits are 100% tested at +25°C, unless otherwise specified. Temperature limits established by characterization and are not production tested.



Typical Performance Curves, 5V Power Supply



FIGURE 1. SFDR vs f_{OUT}, CLOCK = 5MSPS



FIGURE 3. SFDR vs f_{OUT}, CLOCK = 50MSPS







FIGURE 2. SFDR vs f_{OUT}, CLOCK = 25MSPS











Typical Performance Curves, 5V Power Supply (Continued)



FIGURE 7. SFDR vs AMPLITUDE, $f_{CLK}/f_{OUT} = 5$



FIGURE 9. SFDR vs I_{OUT}, CLOCK = 100MSPS



FIGURE 11. SFDR vs TEMPERATURE, CLOCK = 100MSPS



AMPLITUDE (TOTAL PEAK POWER OF COMBINED TONES) (dBFS)

FIGURE 8. SFDR vs AMPLITUDE OF TWO TONES, $f_{CLK}/f_{OUT} = 7$



FIGURE 10. DIFFERENTIAL vs SINGLE-ENDED, CLOCK = 100MSPS



FIGURE 12. SINGLE TONE SFDR



Typical Performance Curves, 5V Power Supply (Continued)



FIGURE 13. TWO TONE, CLOCK = 100MSPS



FIGURE 15. EIGHT-TONE, CLOCK = 100MSPS



FIGURE 17. DIFFERENTIAL NONLINEARITY



FIGURE 14. FOUR-TONE, CLOCK = 100MSPS







FIGURE 18. INTEGRAL NONLINEARITY



Typical Performance Curves, 5V Power Supply (Continued)



FIGURE 19. POWER vs CLOCK RATE, $f_{CLK}/f_{OUT} = 10$, $I_{OUT} = 20mA$

Typical Performance Curves, 3V Power Supply



FIGURE 20. SFDR vs f_{OUT}, CLOCK = 5MSPS











FIGURE 23. SFDR vs f_{OUT}, CLOCK = 100MSPS



Typical Performance Curves, 3V Power Supply (Continued)



FIGURE 24. SFDR vs f_{OUT}, CLOCK = 125MSPS



FIGURE 26. SFDR vs AMPLITUDE, $f_{CLK}/f_{OUT} = 5$



FIGURE 28. SFDR vs I_{OUT}, CLOCK = 100MSPS



FIGURE 25. SFDR vs AMPLITUDE, f_{CLK}/f_{OUT} = 10



FIGURE 27. SFDR vs AMPLITUDE OF TWO TONES, f_{CLK}/f_{OUT} = 7







Typical Performance Curves, 3V Power Supply (Continued)



FIGURE 30. SFDR vs TEMPERATURE, CLOCK = 100MSPS







FIGURE 34. EIGHT-TONE, CLOCK = 100MSPS











FIGURE 35. FOUR-TONE, CLOCK = 50MSPS

Typical Performance Curves, 3V Power Supply (Continued)



FIGURE 36. DIFFERENTIAL NONLINEARITY





FIGURE 38. POWER vs CLOCK RATE, f_{CLK}/f_{OUT} = 10, I_{OUT} = 20mA

Timing Diagrams





FIGURE 39. OUTPUT SETTLING TIME DIAGRAM

FIGURE 40. PEAK GLITCH AREA (SINGLET) MEASUREMENT METHOD



FIGURE 41. PROPAGATION DELAY, SETUP TIME, HOLD TIME AND MINIMUM PULSE WIDTH DIAGRAM

Definition of Specifications

Integral Linearity Error, INL, is the measure of the worst case point that deviates from a best fit straight line of data values along the transfer curve.

Differential Linearity Error, DNL, is the measure of the step size output deviation from code to code. Ideally the step size should be 1 LSB. A DNL specification of 1 LSB or less guarantees monotonicity.

Output Settling Time, is the time required for the output voltage to settle to within a specified error band measured from the beginning of the output transition. The

measurement was done by switching from code 0 to 256, or quarter scale. Termination impedance was 25Ω due to the parallel resistance of the output 50Ω and the oscilloscope's 50Ω input. This also aids the ability to resolve the specified error band without overdriving the oscilloscope.

Singlet Glitch Area, is the switching transient appearing on the output during a code transition. It is measured as the area under the overshoot portion of the curve and is expressed as a Volt-Time specification. This is tested under the same conditions as "Output Settling Time, (tSETT)" on page 6



Full Scale Gain Error, is the error from an ideal ratio of 32 between the output current and the full scale adjust current (through R_{SET}).

Full Scale Gain Drift, is measured by setting the data inputs to all ones and measuring the output voltage through a known resistance as the temperature is varied from T_{MIN} to T_{MAX} . It is defined as the maximum *deviation* from the *value* measured at room temperature to the *value* measured at either T_{MIN} or T_{MAX} . The units are ppm of FSR (full scale range) per °C.

Total Harmonic Distortion, THD, is the ratio of the DAC output fundamental to the RMS sum of the first five harmonics.

Spurious Free Dynamic Range, SFDR, is the amplitude difference from the fundamental to the largest harmonically or non-harmonically related spur within the specified window.

Output Voltage Compliance Range, is the voltage limit imposed on the output. The output impedance load should be chosen such that the voltage developed does not violate the compliance range.

Offset Error, is measured by setting the data inputs to all zeros and measuring the output voltage through a known resistance. Offset error is defined as the maximum *deviation* of the output current from a value of 0mA.

Offset Drift, is measured by setting the data inputs to all zeros and measuring the output voltage through a known resistance as the temperature is varied from T_{MIN} to T_{MAX} . It is defined as the maximum *deviation* from the *value* measured at room temperature to the *value* measured at either T_{MIN} or T_{MAX} . The units are ppm of FSR (Full Scale Range) per °C.

Power Supply Rejection, is measured using a single power supply. Its nominal +5V is varied $\pm 10\%$ and the change in the DAC full scale output is noted.

Reference Input Multiplying Bandwidth, is defined as the 3dB bandwidth of the voltage reference input. It is measured by using a sinusoidal waveform as the external reference with the digital inputs set to all 1s. The frequency is increased until the amplitude of the output waveform is 0.707 of its original value.

Internal Reference Voltage Drift, is defined as the maximum *deviation* from the *value* measured at room temperature to the *value* measured at either T_{MIN} or T_{MAX} . The units are ppm per °C.

Detailed Description

The HI5728 is a dual, 10-bit, current out, CMOS, digital to analog converter. Its maximum update rate is 125MSPS and can be powered by either single or dual power supplies in the recommended range of +3V to +5V. It consumes less than 330mW of power when using a +5V supply with the data switching at 100MSPS. The architecture is based on a segmented current source arrangement that reduces glitch by reducing the amount of current switching at any one time. The five MSBs are represented by 31 major current sources of equivalent current. The five LSBs are comprised of binary weighted current sources. Consider an input waveform to the converter which is ramped through all the codes from 0 to 1023. The five LSB current sources would begin to count up. When they reached the all high state (decimal value of 31) and needed to count to the next code, they would all turn off and the first major current source would turn on. To continue counting upward, the 5 LSBs would count up another 31 codes, and then the next major current source would turn on and the five LSBs would all turn off. The process of the single, equivalent, major current source turning on and the five LSBs turning off each time the converter reaches another 31 codes greatly reduces the glitch at any one switching point. In previous architectures that contained all binary weighted current sources or a binary weighted resistor ladder, the converter might have a substantially larger amount of current turning on and off at certain, worst-case transition points such as mid-scale and quarter scale transitions. By greatly reducing the amount of current switching at certain 'major' transitions, the overall glitch of the converter is dramatically reduced, improving settling times and transient problems.

Digital Inputs And Termination

The HI5728 digital inputs are guaranteed to CMOS levels. However, TTL compatibility can be achieved by lowering the supply voltage to 3V due to the digital threshold of the input buffer being approximately half of the supply voltage. The internal register is updated on the rising edge of the clock. To minimize reflections, proper termination should be implemented. If the lines driving the clock(s) and digital inputs are 50Ω lines, then 50Ω termination resistors should be placed as close to the converter inputs as possible.

Ground Plane(s)

If separate digital and analog ground planes are used, then all of the digital functions of the device and their corresponding components should be over the digital ground plane and terminated to the digital ground plane. The same is true for the analog components and the analog ground plane. Refer to the Application Note on the HI5728 Evaluation Board for further discussion of the ground plane(s) upon availability.

Noise Reduction

To minimize power supply noise, 0.1μ F capacitors should be placed as close as possible to the converter's power supply pins, AV_{DD} and DV_{DD}. Also, should the layout be designed using separate digital and analog ground planes, these capacitors should be terminated to the digital ground for DV_{DD} and to the analog ground for AV_{DD}. Additional filtering of the power supplies on the board is recommended. See the Application Note on the HI5728 Evaluation Board for more information upon availability.



Voltage Reference

The internal voltage reference of the device has a nominal value of +1.2V with a ± 60 ppm/°C drift coefficient over the full temperature range of the converter. It is recommended that a 0.1 μ F capacitor be placed as close as possible to the REFIO pin, connected to the analog ground. The REFLO pin (15) selects the reference. The internal reference can be selected if pin 15 is tied low (ground). If an external reference is desired, then pin 15 should be tied high (to the analog supply voltage) and the external reference driven into REFIO, pin 23. The full scale output current of the converter is a function of the voltage reference used and the value of R_{SET}. I_{OUT} should be within the 2mA to 20mA range, through operation below 2mA is possible, with performance degradation.

If the internal reference is used, V_{FSADJ} will equal approximately 1.16V (pin 22). If an external reference is used, V_{FSADJ} will equal the external reference. The calculation for I_{OUT}(Full Scale) is:

$$I_{OUT}(Full Scale) = V_{FSADJ} / R_{SET} \times 32$$
 (EQ. 1)

If the full scale output current is set to 20mA by using the internal voltage reference (1.16V) and a 1.86k Ω R_{SET} resistor, then the input coding to output current will resemble the following:

INPUT CODE (D9-D0)	IOUTA (mA)	IOUTB (mA)
11111 11111	20	0
10000 00000	10	10
00000 00000	0	20

	NUDUT				
IABLE 1.	INPUT	CODING	vs OUTPUT	CURRENT	(Per DAC)

Outputs

IOUTA and IOUTB (or QOUTA and QOUTB) are

complementary current outputs. The sum of the two currents is always equal to the full scale output current minus one LSB. If single ended use is desired, a load resistor can be used to convert the output current to a voltage. It is recommended that the unused output be either grounded or equally terminated. The voltage developed at the output must not violate the output voltage compliance range of -0.3V to 1.25V. R_{LOAD} should be chosen so that the desired output voltage is produced in conjunction with the output full scale current, which is described above in the 'Reference' section. If a known line impedance is to be driven, then the output load resistor should be chosen to match this impedance. The output voltage equation is:

$$V_{OUT} = I_{OUT} \times R_{LOAD}$$
 (EQ. 2)

These outputs can be used in a differential-to-single-ended arrangement to achieve better harmonic rejection. The SFDR measurements in this data sheet were performed with a 1:1 transformer on the output of the DAC (see Figure 1). With the center tap grounded, the output swing of pins 16 and 17 will be biased at zero volts. It is important to note here that the negative voltage output compliance range limit is -300mV, imposing a maximum of $600mV_{P-P}$ amplitude with this configuration. The loading as shown in Figure 1 will result in a 500mV signal at the output of the transformer if the full scale output current of the DAC is set to 20mA.





 $V_{OUT} = 2 \times I_{OUT} \times R_{EQ}$, where R_{EQ} is ~12.5 Ω .

Allowing the center tap to float will result in identical transformer output, however the output pins of the DAC will have positive DC offset. The 50Ω load on the output of the transformer represents the spectrum analyzer's input impedance.



Thin Plastic Quad Flatpack Packages (LQFP)



Q48.7x7A (JEDEC MS-026BBC ISSUE B) 48 LEAD THIN PLASTIC QUAD FLATPACK PACKAGE

	INC	HES	MILLIN	MILLIMETERS				
SYMBOL	MIN	MAX	MIN	MAX	NOTES			
А	-	0.062	-	1.60	-			
A1	0.002	0.005	0.05	0.15	-			
A2	0.054	0.057	1.35	1.45	-			
b	0.007	0.010	0.17	0.27	6			
b1	0.007	0.009	0.17	0.23	-			
D	0.350	0.358	8.90	9.10	3			
D1	0.272	0.280	6.90	7.10	4, 5			
E	0.350	0.358	8.90	9.10	3			
E1	0.272	0.280	6.90	7.10	4, 5			
L	0.018	0.029	0.45	0.75	-			
Ν	4	48		48				
е	0.020 BSC		0.50	-				

NOTES:

- 1. Controlling dimension: MILLIMETER. Converted inch dimensions are not necessarily exact.
- 2. All dimensions and tolerances per ANSI Y14.5M-1982.
- 3. Dimensions D and E to be determined at seating plane -C-.

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- 4. Dimensions D1 and E1 to be determined at datum plane -H- .
- 5. Dimensions D1 and E1 do not include mold protrusion. Allowable protrusion is 0.25mm (0.010 inch) per side.
- 6. Dimension b does not include dambar protrusion. Allowable dambar protrusion shall not cause the lead width to exceed the maximum b dimension by more than 0.08mm (0.003 inch).
- 7. "N" is the number of terminal positions.

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